Intertek

Report No.: 130918055GZU-001 Issued: 24 January 2014

#### **TEST REPORT**

Applicant Name &	;	Shenzhen SOFARSOLAR Co., Ltd.
Address		3A-1, Huake Building, East Technology Park, Qiaoxiang Road, Nanshan District, Shenzhen, China
Manufacturing Site	:	Suga Networks Equipment (Shenzhen) Co., Ltd.
0		Floor 1 East & Floor 2 of Building B(Manufacturing Site), Floor 3 & 4 of Building A(Office Site), Block 12, Xi Cheng Industrial Park, Xi Xiang Street, BaoAn District, Shenzhen City, China
Sample Description		
Product	:	Grid-connected PV inverter
Model No.	:	Sofar 20000TL-Sx, Sofar 17000TL-Sx, Sofar 15000TL-Sx, Sofar 10000TL-Sx
Electrical Dating		(x=0-6) Maximum dia imput weltaasi 1000 M
Electrical Rating	:	Maximum d.c. input voltage: 1000 V Input voltage rang: 250-960 V
		Operating temperature range: $-25 \sim 60^{\circ}$ C
		(See page 5 for details)
Date Received	:	18 September 2013
Date Test Conducted		23 November 2013-26 November 2013
Test standards		EN 61000-6-3: 2007+A1: 2011
		EN 61000-6-1: 2007
Test Result	:	Pass
Conclusion	:	The submitted samples complied with the above EMC standards.
Remark	2	None.
*****	****	******************End of Page************************************

Prepared and Checked By:

mp

Ivan Zhou **Project Engineer** Intertek Guangzhou

rleden Ma Signature Helen Ma

Sr. Project Engineer Intertek Guangzhou 24 January 2014 Date

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Approved By:

Intertek Testing Services Shenzhen Ltd. Guangzhou Branch

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## **TEST RESULTS SUMMARY**

Test Item	Standard	Result
Continuous conducted disturbance	EN 61000-6-3:2007+A1: 2011	Pass
voltage	<b>Reference: EN 55022: 2010</b>	
Discontinuous conducted disturbance	EN 61000-6-3:2007+A1: 2011	Pass
voltage	Reference: EN 55014-1: 2006+A1: 2009	
Emission at Telecommunications/	EN 61000-6-3:2007+A1: 2011	N/A
network Ports	<b>Reference: EN 55022: 2010</b>	
Radiated emission (30 MHz–1000 MHz)	EN 61000-6-3:2007+A1: 2011	Pass
×	<b>Reference: EN 55022: 2010</b>	
Radiated emission (1 GHz-6 GHz)	EN 61000-6-3:2007+A1: 2011	N/A
	<b>Reference: EN 55022: 2010</b>	
Harmonic of current	EN 61000-6-3:2007+A1: 2011	Pass
	Reference: EN 61000-3-12:2011	
Flicker	EN 61000-6-3:2007+A1: 2011	Pass
	Reference: EN 61000-3-11:2000	
ESD immunity	EN 61000-6-1:2007	Pass
U U	Reference: EN 61000-4-2: 1995+A1: 1998+A2:	
	2001	
Radiated EM field immunity	EN 61000-6-1:2007	Pass
2	Reference: EN 61000-4-3: 2006	
EFT immunity	EN 61000-6-1:2007	Pass
·	Reference: EN 61000-4-4: 2004	
Surge immunity	EN 61000-6-1:2007	Pass
ð v	Reference: EN 61000-4-5: 2006	
Inject current immunity	EN 61000-6-1:2007	Pass
5	Reference: EN 61000-4-6: 2009	
Power frequency magnetic field immunity	EN 61000-6-1:2007	Pass
<b>1 1 1 1 1 1 1 1 1 1</b>	Reference: EN 61000-4-8: 1993+A1: 2001	
Voltage dips and interruption immunity	EN 61000-6-1:2007	N/A
	Reference: EN 61000-4-11: 2004	

**Remark:** 

1.

The symbol "N/A" in above table means <u>Not Applicable</u>. When determining the test results, measurement uncertainty of tests has been considered. 2.



2

#### **EMC Results Conclusion**

(with Justification)

RE: EMC Testing Pursuant to EMC Directive 2004/108/EC Performed On the Gridconnected PV inverter, Models: Sofar 20000TL-Sx, Sofar 17000TL-Sx, Sofar 15000TL-Sx, Sofar 10000TL-Sx (x=0-6).

We tested the Grid-connected PV inverter, Model: Sofar 20000TL-S6, to determine if it was in compliance with the relevant EN standards as marked on the Test Results Summary. We found that the unit met the requirement of EN 61000-6-3, EN 61000-6-1 (EN 61000-4-2), EN 61000-6-1 (EN 61000-4-4), EN 61000-6-1 (EN 61000-4-6), EN 61000-6-1 (EN 61000-4-5), EN 61000-6-1 (EN 61000-4-3), EN 61000-6-1 (EN 61000-4-8) & EN 61000-6-1(EN 61000-4-11) standards when tested as received. The worst case's test data was presented in this test report.

#### **Electrical Rating:**

Maximum d.c. input voltage: 1000 V Input voltage rang: 250-960 V Max. input current: 2×24 A (for Sofar 20000TL-Sx); 2×21 A (for Sofar 17000TL-Sx, Sofar 15000TL-Sx); 2×15 A (for Sofar 10000TL-Sx) Max. PV Isc: 2×30 A (for Sofar 20000TL-Sx); 2×27 A (for Sofar 17000TL-Sx, Sofar 15000TL-Sx); 2×20 A (for Sofar 10000TL-Sx) Nominal output voltage: 3/N/PE230V/400V Max. output current: 3×29 A (for Sofar 20000TL-Sx); 3×25 A (for Sofar 17000TL-Sx); 3×22 A (for Sofar 15000TL-Sx); 3×15 A (for Sofar 10000TL-Sx) Nominal frequency: 50 Hz Max. output power: 20000 W (for Sofar 20000TL-Sx); 17000 W (for Sofar 17000TL-Sx); 15000 W (for Sofar 15000TL-Sx); 10000 W (for Sofar 10000TL-Sx) Ingress protection: IP65 Operating temperature range: -25~60°C

#### General product information:

Product covered by this report is grid-connected PV inverter for indoor or outdoor installation. The connection to the DC input and AC output are through connectors. The structure of the unit complied with the IP 65 requirement.

The inverters intended to operate at ambient temperature  $-25^{\circ}$ C  $-+60^{\circ}$ C and 250-960 Vdc input, which will be specified in the user manual, the inverters will output full power when operated at 45°C. If operated at higher than 45°C temperature, the output power derating.

For all models, if the DC input voltage is higher than 850 Vdc the output power will be derating. For model Sofar 20000TL-Sx, if the DC input voltage is lower than 430 Vdc, the output power will be derating.



For model Sofar 17000TL-Sx, if the DC input voltage is lower than 420 Vdc, the output power will be derating.

For model Sofar 15000TL-Sx, if the DC input voltage is lower than 370 Vdc, the output power will be derating.

For model Sofar 10000TL-Sx, if the DC input voltage is lower than 350 Vdc, the output power will be derating.

For all models, if the AC output voltage is lower than 230 Vac the output current will be limited to not higher than rated output current.

All the models have identical mechanical and electrical construction except some componnents and some parameter of the software architecture in order to control the max output power.

Other than special notice, the model Sofar 20000TL-S6 is as the representative test models in this report

The production units are required to conform to the initial sample as received when the units are placed on the market.



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### LABORATORY MEASUREMENTS

#### **Configuration Information**

<b>Equipment Under Test (EUT)</b> :	Grid-connected PV inverter			
Model:	Sofar 20000TL-S6			
Serial No.	Not Labeled			
Support Equipment:	AC-DC source provided by client			
Rated Voltage:	Input: 720VDC; Output: 400V, 50Hz, 3phases			
Condition of Environment:	Temperature:22~28°CRelative Humidity:35~60%Atmosphere Pressure86~106kPa			

#### Notes:

1. The EMI measurements had been made in the operating mode producing the largest emission in the frequency band being investigated consistent with normal applications.

An attempt had be made to maximize the emission by varying the configuration of the EUT.

2. The EMS measurements had been made in the frequency bands being investigated, with the EUT in the most susceptible operating mode consistent with normal applications. The configuration of the test sample had been varied to achieve maximum susceptibility.



#### 4 EMI TEST

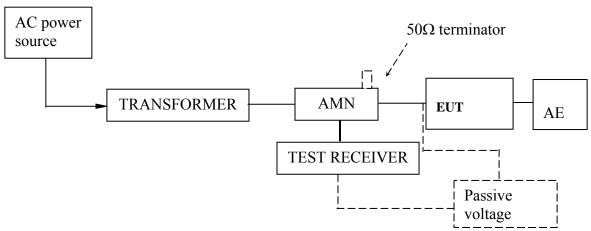
#### 4.1 Emission- Low voltage AC mains port (continuous disturbance)

#### **Test Result: Pass**

#### 4.1.1 Used Test Equipment

Equipment No.	Equipment	Model	Manufacturer
828985/018	Test Receiver	ESCS30	Rohde & Schwarz
8129-203	L.I.S.N.	NNLK8129	Schwarzbeck
M20531	50Ω Coaxial Switch	MP59B	Anritsu
100006	Pulse Limiter	ESH3-Z2	Rohde & Schwarz

#### 4.1.2 Block Diagram of Test Setup



#### 4.1.3 Test Setup and Procedure

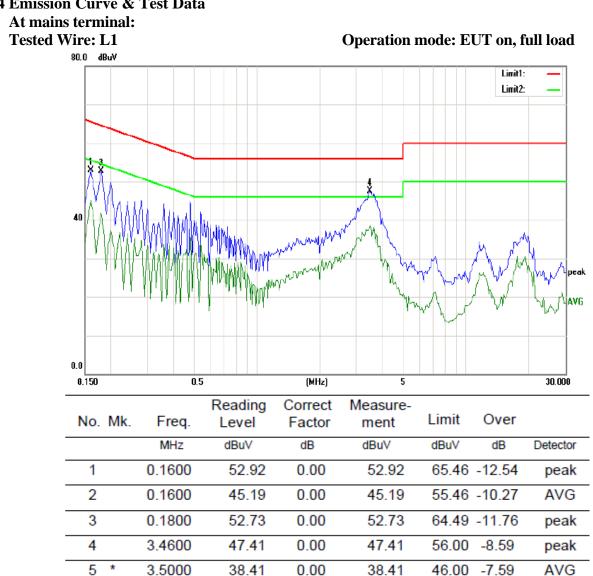
The EUT was set to achieve the maximum emission level. The mains terminal disturbance voltage was measured with the EUT in a shielded room. The EUT was connected to AC power source through an Artificial Mains Network which provides a  $50\Omega$  linear impedance Artificial hand is used if appropriate (for handheld apparatus). The load/control terminal disturbance voltage was measured with passive voltage probe if appropriate.

The EUT was placed on a 0.8m high non-metallic table above a metallic plane, and 0.4m from wall of shielded room which is considered as Ground Reference Plane (GRP) (For floor standing EUT, was placed on a 0.1m high non-metallic supported on GRP) The EUT keeps a distance of at least 0.8m from any other of the metallic surface. The Artificial Mains Network is situated at a distance of 0.8m from the EUT.

During the test, mains lead of EUT excess 0.8m was folded back and forth parallel to the lead so as to form a horizontal bundle with a length between 0.3m and 0.4m.

The bandwidth of test receiver was set at 9 kHz. The frequency range from 150 kHz to 30MHz was checked.

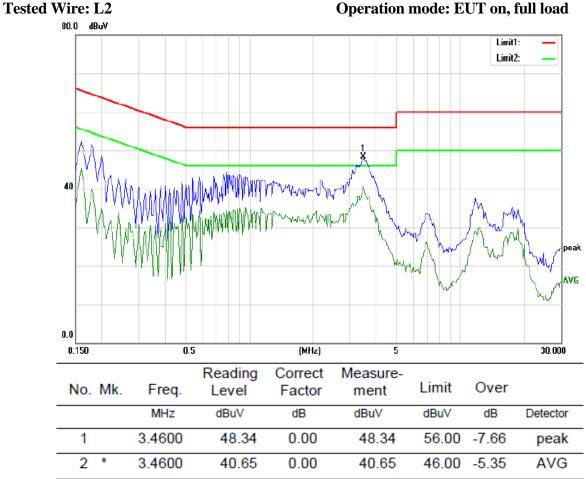




4.1.4 Emission Curve & Test Data

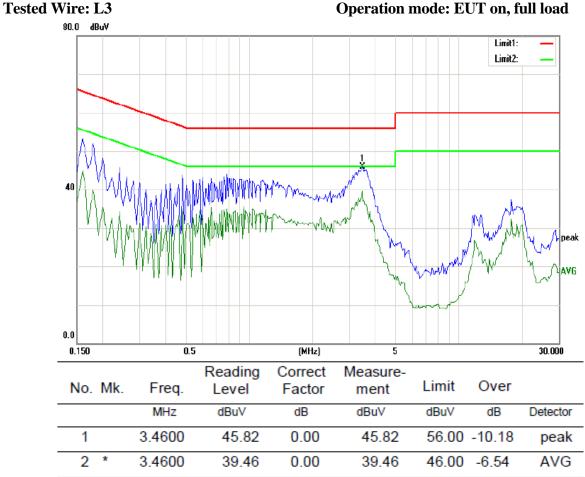
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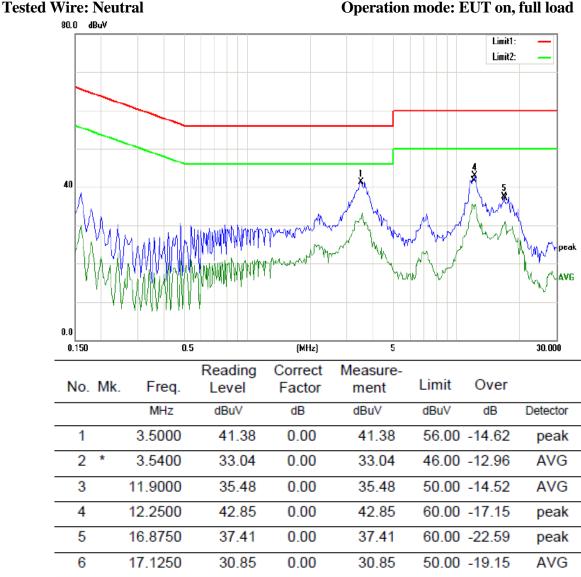


**Operation mode: EUT on, full load** 









#### **Operation mode: EUT on, full load**

#### **4.1.5 Measurement Uncertainty**

The measurement uncertainty describes the overall uncertainty of the given measured value during the operation of the EUT.

Measurement uncertainty is calculated in accordance with CISPR 16-4-2:2003.

Measurement uncertainty of mains terminal disturbance voltage in CISPR band B: 2.6dB. The measurement uncertainty is given with a confidence of 95%, k=2.

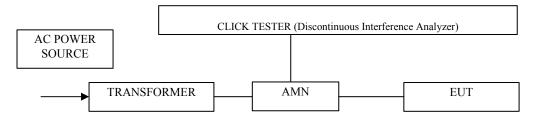


4.2 Emission- Low voltage AC mains port (discontinuous disturbance) Test Result: Pass

#### 4.2.1 Used Test Equipment

Equipment No.	Equipment	Model	Manufacturer
828985/018	Test Receiver	ESCS30	Rohde & Schwarz
8129-203	L.I.S.N.	NNLK8129	Schwarzbeck
M20531	50Ω Coaxial Switch	MP59B	Anritsu
100006	Pulse Limiter	ESH3-Z2	Rohde & Schwarz

#### 4.2.2 Block Diagram of Test Setup



#### 4.2.3 Test Setup and Procedure

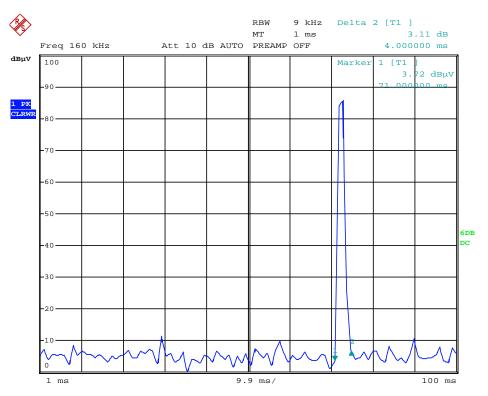
The EUT was placed on a 0.8m high non-metallic table in shielded room, the wall of shielded room used as Ground Reference Plane (GRP), and keeps a distance of at least 0.8m from any of the other metallic surface.

The EUT was connected to an artificial mains network and at a distance of 0.8m from it, the excess lead of EUT was bundled with a length of 0.3m to 0.4m parallel to the main lead. The number of counted clicks above the permitted limit for continuous interference and their duration, spacing and rate were measured during the observation time. When relevant, a permitted (relaxed) limit for clicks were calculated and a second measurement was performed. Determination of compliance with the permitted limit according to the upper quartile method was

applied. The frequency 150kHz, 500kHz, 1.4MHz and 30MHz was checked.



#### 4.2.4 Test Data



The appliance was deemed to comply with the limits if fulfilling the three conditions below: – the click rate is not more than 5.

- none of the caused clicks has a duration longer than 20 ms.

-90 % of the caused clicks have a duration less than 10 ms.

#### 4.2.5 Measurement Uncertainty

The measurement uncertainty for click test is under consideration according to CISPR 16-4-2:2003.

#### 4.3 Emission- DC power port

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Test Result: Not Applicable
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**Remark:** These DC ports of appliance are only intended for connection to solar battery modules.

#### 4.4 Emission- Telecommunications/network port

#### **Test Result: Not Applicable**

**Remark:** The test only apply to balanced telecommunication ports intended for connection to unscreened balanced pairs

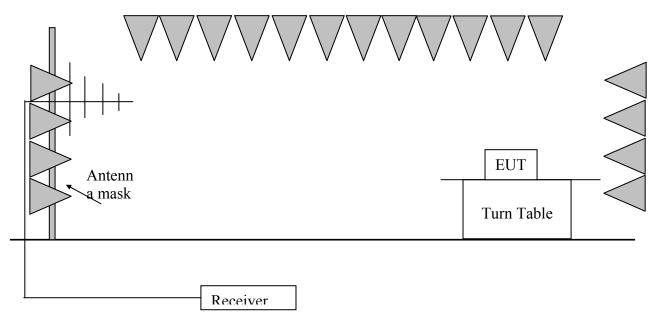


#### 4.5 Emission- Enclosure port Test Result: Pass

#### 4.5.1 Used Test Equipment

Equip. No.	Equipment	Model	Manufacturer
101045	EMI Test Receiver	ESCI	Rohde & Schwarz
22013	Pre-Amplifier	PAP-0203	CD
141	Bilog Antenna	VULB9163	Schwarzbeck

#### 4.5.2 Block Diagram of Test Setup



#### 4.5.3 Test Setup and Procedure

The measurement was applied in a semi-anechoic chamber. The EUT and simulators were placed on a 0.8m high wooden turntable above the horizontal metal ground plane. The turn table rotated 360 degrees to determine the position of the maximum emission level. The EUT was set 3 meters away from the receiving antenna which was mounted on an antenna mask. The antenna moved up and down between from 1 meter to 4 meters to find out the maximum emission level. Broadband antenna was used as receiving antenna. Both horizontal and vertical polarization of the antenna was set on measurement. In order to find the maximum emission, all of the interface cables were manipulated according to EN55022 requirement during radiated test.

The bandwidth setting on R&S Test Receiver was 120 kHz.

The frequency range from 30MHz to 1000MHz was checked

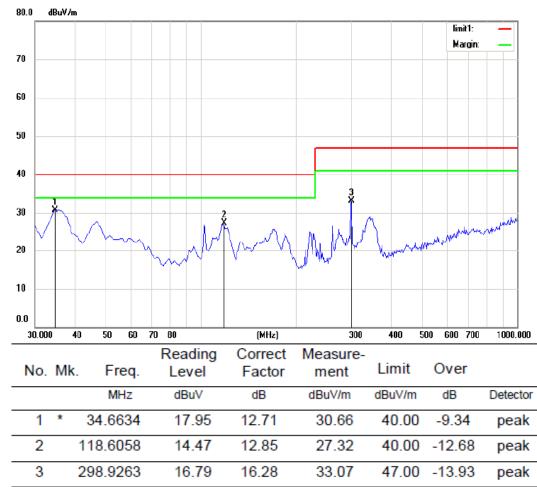


#### 4.5.4 Test Curve & Test Data

#### 80.0 dBuV/m limit1: Margin: 70 60 50 40 Į, 30 Luff Mar 20 10 0.0 60 70 80 (MHz) 500 600 700 30.000 40 50 300 400 1000.000 Reading Correct Measure-No. Mk. Freq. Limit Over Level Factor ment MHz dBuV dB dBuV/m dB dBuV/m Detector 103.0610 20.53 14.06 34.59 40.00 -5.41 1 \* peak 2 298.9263 23.15 16.29 39.44 47.00 -7.56 peak

#### **Operation mode: EUT on, full load** Horizontal





#### Vertical

#### 4.5.5 Measurement uncertainty

The measurement uncertainty describes the overall uncertainty of the given measured value during the operation of the EUT.

Measurement uncertainty is calculated in accordance with CISPR 16-4-2:2003.

Measurement uncertainty of radiated emission: 3.3 dB.

The measurement uncertainty is given with a confidence of 95%, k=2.

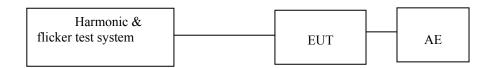


#### 4.6 Harmonic of Current Test Result: Pass

#### 4.6.1 Used Test Equipment

esea rese zquip			
Equip. No.	Equipment	Model	Manufacturer
1305A02873	45KVA AC Power source	NSG 1007-45/45KVA	Teseq
1305A02873	Signal conditioning Unit	CCN 1000-3	Teseq
1305A02873	Three phase impedance network	INA2197/37A	Teseq
1305A02874	Three phase impedance network	INA 2196/75A	Teseq
A22714	Profline 2100 AC Switching Unit	NSG2200-3	Teseq

#### 4.6.2 Block Diagram of Test Setup



#### 4.6.3 Test Setup and Procedure

Harmonics of the fundamental current were measured up to 40 order harmonics using a digital power meter with an analogue output and frequency analyser which was integrated in the harmonic & flicker test system. The measurements were carried out under steady conditions.

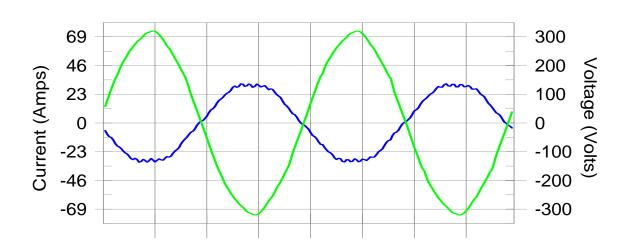
# □ This product is not defined as lighting equipment, and has rated power less than 75W, therefore, no limit apply according to EN 61000-3-2.



4.6.4 Test Data

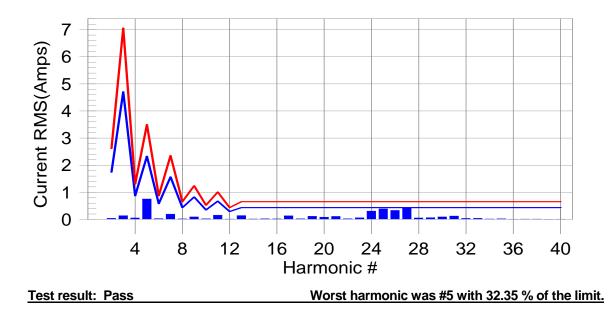


Current & voltage waveforms



#### Harmonics and Class 2 limit line

**European Limits** 





#### **Current Test Result Summary (Phase A-Run time)**

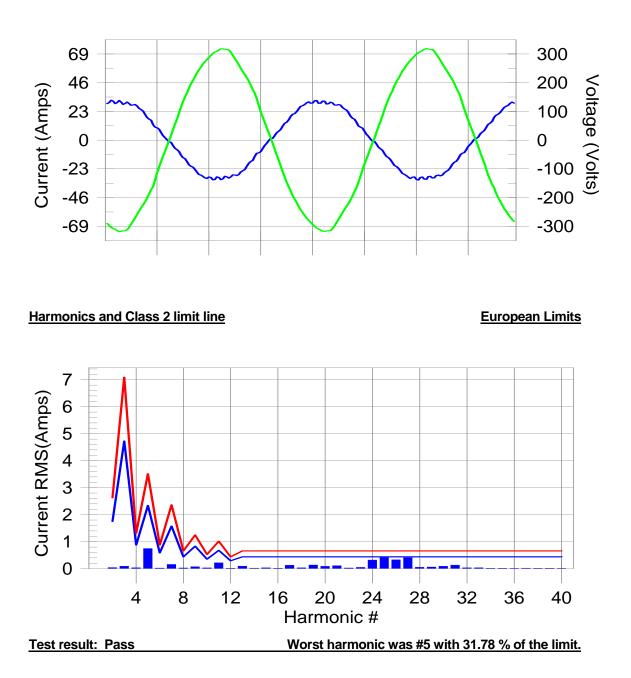
I-THD(%	b): 4.602 L	imit(%): 23.000	) PWHE	D(%): 13.753	PWHD Limit	(%): 23.000	
•	parameter va V_RMS (Volts I_Peak (Amps) I <sub>1</sub> -Ref (Amps) Power (Watts	s): 32.982 ): 21.836	est:	Frequency(Hz): I_RMS (Amps): Crest Factor: Power Factor:	49.99 22.373 1.480 -0.998		
Harm#	Harms(avg)	100%Limit	%of Limit	Harms(max)	150%Limit	%of Limit	Status
2 3 4 5 6 7 8 9 10 11 12 13 14 15	0.027 0.130 0.047 0.745 0.024 0.185 0.016 0.083 0.021 0.139 0.011 0.129 0.015 0.021	4.708 0.872 2.332 0.581 1.569 0.436 0.828 0.349 0.676 0.291 0.436 N/A	1.5 2.8 5.4 31.9 4.1 11.8 3.7 10.0 5.9 20.5 3.6 29.5 N/A N/A	0.040 0.140 0.056 0.756 0.032 0.197 0.020 0.094 0.023 0.159 0.014 0.143 0.018 0.025	2.616 7.062 1.308 3.498 0.872 2.354 0.654 1.242 0.523 1.014 0.436 0.654 N/A N/A	1.52 1.99 4.24 21.62 3.68 8.36 3.11 7.60 4.49 15.71 3.21 21.84 N/A N/A	Pass Pass Pass Pass Pass Pass Pass Pass
16 17 18 19 20 21 22	0.016 0.124 0.014 0.111 0.038 0.097 0.020	N/A N/A N/A N/A N/A N/A	N/A N/A N/A N/A N/A N/A	0.019 0.134 0.026 0.119 0.085 0.112 0.029	N/A N/A N/A N/A N/A N/A	N/A N/A N/A N/A N/A N/A	N/A N/A N/A N/A N/A N/A
23 24 25 26 27 28 29 30	0.052 0.115 0.342 0.129 0.377 0.032 0.061 0.038	N/A N/A N/A N/A N/A	N/A N/A N/A N/A N/A N/A N/A	0.060 0.309 0.388 0.333 0.429 0.054 0.066 0.094	N/A N/A N/A N/A N/A N/A	N/A N/A N/A N/A N/A N/A N/A	N/A N/A N/A N/A N/A N/A N/A
31 32 33 34 35 36 37 38 39 40	0.030 0.111 0.021 0.037 0.014 0.021 0.012 0.012 0.013 0.006 0.007	N/A N/A N/A N/A N/A N/A N/A N/A	N/A N/A N/A N/A N/A N/A N/A N/A	0.127 0.038 0.042 0.017 0.024 0.011 0.014 0.014 0.009 0.012	N/A N/A N/A N/A N/A N/A N/A N/A	N/A N/A N/A N/A N/A N/A N/A N/A N/A	N/A N/A N/A N/A N/A N/A N/A N/A N/A

Note: Measured reference fundamental current limits were applied for this test.





#### Current & voltage waveforms





#### **Current Test Result Summary (Phase B-Run time)**

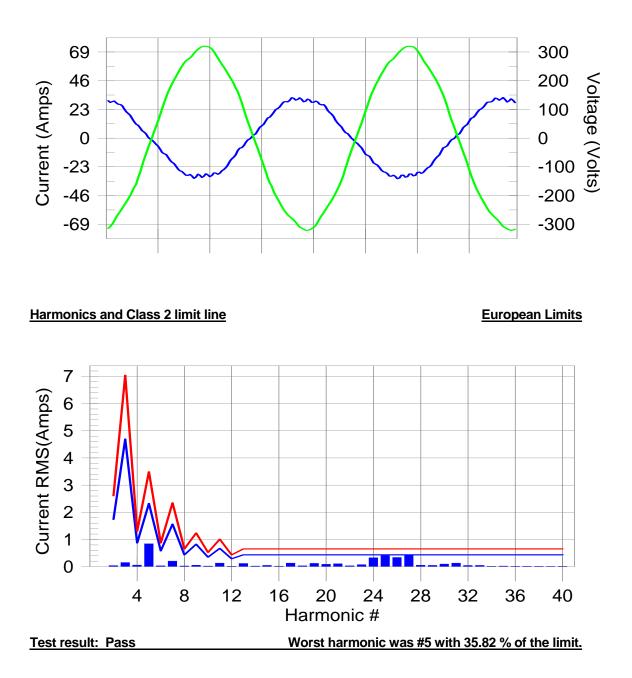
I-THD(%	): 4.497 Liı	mit(%): 23.000	D PWH	D(%): 13.689	PWHD Limit	(%): 23.000	
Highest parameter values during test:       V_RMS (Volts):       222.45       Frequency(Hz):       49.99         I_Peak (Amps):       33.647       I_RMS (Amps):       22.451         I <sub>1</sub> -Ref (Amps):       21.921       Crest Factor:       1.504         Power (Watts):       -4964       Power Factor:       -0.998							
Harm#	Harms(avg)	100%Limit	%of Limit	Harms(max)	-0.990 150%Limit	%of Limit	Status
2	0.024	1.751	1.4	0.039	2.627	1.49	Pass
3	0.083	4.728	1.7	0.091	7.093	1.43	Pass
3 4	0.005	0.876	2.9	0.035	1.313	2.68	Pass
4 5	0.023	2.342	31.3	0.035	3.513	2.00	Pass
6	0.733	0.584	2.5	0.023	0.876	21.20	Pass
0 7		0.564 1.576					
	0.139		8.8	0.156	2.364	6.60	Pass
8 9	0.021	0.438	4.8 7.4	0.026	0.657	3.97 5.87	Pass
	0.062	0.832		0.073	1.248		Pass
10	0.024	0.350	7.0	0.028	0.525	5.36	Pass
11	0.195	0.679	28.7	0.216	1.018	21.23	Pass
12	0.012	0.292	4.2	0.015	0.438	3.49	Pass
13	0.078	0.438	17.9	0.095	0.657	14.49	Pass
14	0.018	N/A	N/A	0.021	N/A	N/A	N/A
15	0.029	N/A	N/A	0.033	N/A	N/A	N/A
16	0.013	N/A	N/A	0.017	N/A	N/A	N/A
17	0.123	N/A	N/A	0.126	N/A	N/A	N/A
18	0.015	N/A	N/A	0.030	N/A	N/A	N/A
19	0.124	N/A	N/A	0.136	N/A	N/A	N/A
20	0.036	N/A	N/A	0.086	N/A	N/A	N/A
21	0.099	N/A	N/A	0.113	N/A	N/A	N/A
22	0.018	N/A	N/A	0.026	N/A	N/A	N/A
23	0.038	N/A	N/A	0.048	N/A	N/A	N/A
24	0.124	N/A	N/A	0.319	N/A	N/A	N/A
25	0.363	N/A	N/A	0.414	N/A	N/A	N/A
26	0.126	N/A	N/A	0.328	N/A	N/A	N/A
27	0.356	N/A	N/A	0.405	N/A	N/A	N/A
28	0.031	N/A	N/A	0.050	N/A	N/A	N/A
29	0.056	N/A	N/A	0.063	N/A	N/A	N/A
30	0.038	N/A	N/A	0.089	N/A	N/A	N/A
31	0.115	N/A	N/A	0.131	N/A	N/A	N/A
32	0.017	N/A	N/A	0.030	N/A	N/A	N/A
33	0.029	N/A	N/A	0.034	N/A	N/A	N/A
34	0.012	N/A	N/A	0.015	N/A	N/A	N/A
35	0.016	N/A	N/A	0.019	N/A	N/A	N/A
36	0.009	N/A	N/A	0.012	N/A	N/A	N/A
37	0.015	N/A	N/A	0.019	N/A	N/A	N/A
38	0.012	N/A	N/A	0.014	N/A	N/A	N/A
39	0.012	N/A	N/A	0.015	N/A	N/A	N/A
40	0.009	N/A	N/A	0.011	N/A	N/A	N/A

Note: Measured reference fundamental current limits were applied for this test.





#### Current & voltage waveforms





#### **Current Test Result Summary (Phase C-Run time)**

I-THD(%	): 4.914 Lin	nit(%): 23.000	) PWHC	D(%): 14.352	PWHD Limit	(%): 23.000	
	parameter val V_RMS (Volts) I_Peak (Amps) I₁-Ref (Amps): Power (Watts)	): 225.21 ): 33.100 21.766	est:	Frequency(Hz): I_RMS (Amps): Crest Factor: Power Factor:	49.99 22.300 1.487 -0.997		
Harm#	Harms(avg)	100%Limit	%of Limit	Harms(max)	150%Limit	%of Limit	Status
2	0.025	1.739	1.5	0.040	2.608	1.52	Pass
3	0.143	4.694	3.0	0.151	7.041	2.15	Pass
4	0.047	0.869	5.5	0.059	1.304	4.50	Pass
5	0.819	2.325	35.2	0.839	3.488	24.06	Pass
6	0.024	0.580	4.1	0.033	0.869	3.77	Pass
7	0.195	1.565	12.5	0.207	2.347	8.81	Pass
8	0.023	0.435	5.2	0.027	0.652	4.12	Pass
9	0.041	0.826	5.0	0.053	1.239	4.28	Pass
10	0.019	0.348	5.4	0.023	0.522	4.33	Pass
11	0.100	0.674	14.9	0.131	1.011	12.95	Pass
12	0.012	0.290	4.2	0.015	0.435	3.45	Pass
13	0.108	0.435	24.9	0.118	0.652	18.04	Pass
14	0.018	N/A	N/A	0.022	N/A	N/A	N/A
15	0.044	N/A	N/A	0.048	N/A	N/A	N/A
16	0.016	N/A	N/A	0.019	N/A	N/A	N/A
17	0.122	N/A	N/A	0.131	N/A	N/A	N/A
18	0.016	N/A	N/A	0.032	N/A	N/A	N/A
19	0.111	N/A	N/A	0.119	N/A	N/A	N/A
20	0.037	N/A	N/A	0.088	N/A	N/A	N/A
20	0.096	N/A	N/A	0.109	N/A	N/A	N/A
22	0.020	N/A	N/A	0.030	N/A	N/A	N/A
23	0.065	N/A	N/A	0.030	N/A	N/A	N/A
23	0.003	N/A	N/A	0.330	N/A	N/A	N/A
24 25	0.123	N/A	N/A	0.330	N/A	N/A	N/A
25 26	0.363	N/A N/A	N/A	0.412	N/A	N/A N/A	N/A
20 27	0.135	N/A N/A	N/A	0.339	N/A	N/A	N/A
27	0.389	N/A N/A	N/A	0.440	N/A	N/A N/A	N/A
			N/A		N/A		N/A
29	0.038	N/A		0.047		N/A	
30	0.038	N/A	N/A	0.096	N/A	N/A	N/A
31	0.117	N/A	N/A	0.133	N/A	N/A	N/A
32	0.020	N/A	N/A	0.044	N/A	N/A	N/A
33	0.040	N/A	N/A	0.048	N/A	N/A	N/A
34	0.015	N/A	N/A	0.019	N/A	N/A	N/A
35	0.018	N/A	N/A	0.021	N/A	N/A	N/A
36	0.010	N/A	N/A	0.014	N/A	N/A	N/A
37	0.016	N/A	N/A	0.019	N/A	N/A	N/A
38	0.011	N/A	N/A	0.014	N/A	N/A	N/A
39	0.010	N/A	N/A	0.012	N/A	N/A	N/A
40	0.009	N/A	N/A	0.014	N/A	N/A	N/A

Note: Measured reference fundamental current limits were applied for this test.

#### 4.6.5 Measurement Uncertainty

The measurement uncertainty for harmonic test is under consideration according to CISPR 16-4-2:2003.



#### 4.7 Flicker

#### **Test Result: Pass**

#### 4.7.1 Used Test Equipment

Equip. No.	Equipment	Model	Manufacturer	
1305A02873	45KVA AC Power source	NSG 1007-45/45KVA	Teseq	
1305A02873	Signal conditioning Unit	CCN 1000-3	Teseq	
1305A02873	Three phase impedance network	INA2197/37A	Teseq	
1305A02874	Three phase impedance network	INA 2196/75A	Teseq	
A22714	Profline 2100 AC Switching Unit	NSG2200-3	Teseq	

#### 4.7.2 Block Diagram of Test Setup

Harmonic & flicker test system		EUT		AE
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# 4.7.3 Test Setup and Procedure 4.7.3.1 Definition

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	Flicker:	impression of unsteadiness of visual sensation induced by a lighting stimulus
		whose luminance or spectral distribution fluctuates with time.
	Pst:	Short-term flicker indicator The flicker severity evaluated over a short period (in
		minutes); Pst=1 is the conventional threshold of irritability
	Plt:	long-term flicker indicator; the flicker severity evaluated over a long period (a
		few hous). Using successive Pst valuse.
	dc:	the relative steady-state voltage change
	dmax:	the maximum relative voltage change
	d(t):	the value during a voltage change

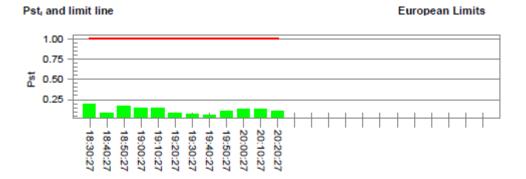
#### 4.7.3.2 Test condition

The EUT was set to produce the most unfavourable sequence of voltage changes.

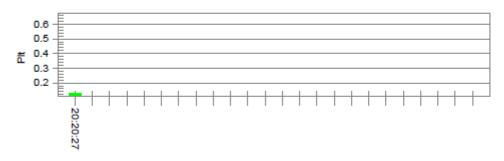


#### 4.7.4 Test Data

#### Flicker Test Summary per EN/IEC61000-3-11 (Phase A-Run time)





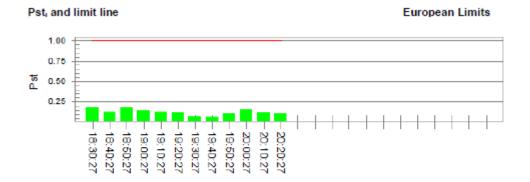


#### Parameter values recorded during the test: Vrms at the end of test (Volt): 228.80

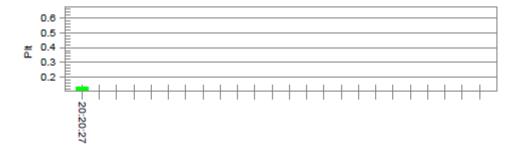
vinis at the chu of test (volt).	220.00			
Highest dt (%):	0.96	Test limit (%):	3.30	Pass
Time(mS) > dt:	0.0	Test limit (mS):	500.0	Pass
Highest dc (%):	0.75	Test limit (%):	3.30	Pass
Highest dmax (%):	0.95	Test limit (%):	6.00	Pass
Highest Pst (10 min. period):	0.192	Test limit:	1.000	Pass
Highest Plt (2 hr. period):	0.132	Test limit:	0.650	Pass



#### Flicker Test Summary per EN/IEC61000-3-11 (Phase B-Run time)



#### Plt and limit line

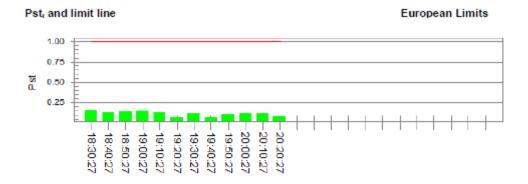


#### Parameter values recorded during the test:

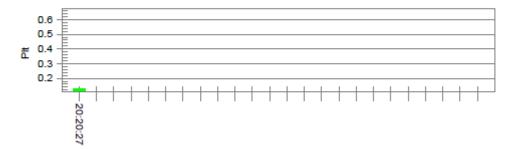
Vrms at the end of test (Volt):	229.75			
Highest dt (%):	0.98	Test limit (%):	3.30	Pass
Time(mS) > dt:	0.0	Test limit (mS):	500.0	Pass
Highest dc (%):	0.75	Test limit (%):	3.30	Pass
Highest dmax (%):	1.01	Test limit (%):	6.00	Pass
Highest Pst (10 min. period):	0.193	Test limit:	1.000	Pass
Highest Plt (2 hr. period):	0.134	Test limit:	0.650	Pass



#### Flicker Test Summary per EN/IEC61000-3-11 (Phase C-Run time)



Plt and limit line



Parameter values recorded dur	ing the test:			
Vrms at the end of test (Volt):	230.11			
Highest dt (%):	0.88	Test limit (%):	3.30	Pass
Time(mS) > dt:	0.0	Test limit (mS):	500.0	Pass
Highest dc (%):	0.72	Test limit (%):	3.30	Pass
Highest dmax (%):	0.91	Test limit (%):	6.00	Pass
Highest Pst (10 min. period):	0.188	Test limit:	1.000	Pass
Highest Plt (2 hr. period):	0.130	Test limit:	0.650	Pass

#### 4.7.5 Measurement Uncertainty

Measurement uncertainty for voltage fluctuation and flicker is under consideration according to CISPR 16-4-2:2003.



#### 5 EMS TEST

#### Performance Criteria:

Criterion A:	The apparatus shall continue to operate as intended during the test. No degradation of performance or loss of function is allowed below a performance level (or permission loss of performance) specified by the
	manufacturer, when the apparatus is used as intended. If the minimum
	performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description and documentation and from what the user may reasonably expect from the apparatus if used as intended.

- Criterion The apparatus shall continue to operate as intended after the test. No B: degradation of performance or loss of function is allowed below a performance level (or permission loss of performance) specified by the manufacturer, when the apparatus is used as intended. During the test, degradation of performance is allowed, however, no change of actual operating state or stored data is allowed. If the minimum performance level or the permissible performance loss is not specified by the manufacturer, then either of these may be derived from the product description, and documentation, and from what the user may reasonably expect from the apparatus if used as intended.
- Criterion C: Temporary loss of function is allowed, provided the function is self-recoverable or can be restored by the operation of the controls, or by any operation specified in the instruction for use.

#### **Measurement Uncertainty**

According to CISPR 16-4-2:2003, measurement uncertainty to immunity test is under consideration.

5.1 Electrostatic Discharge Immunity

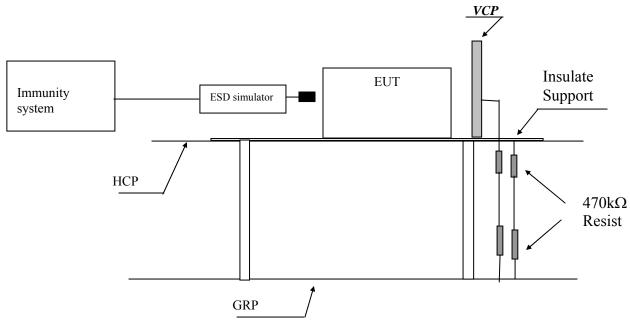
Tested Port: Enclosure Performance criterion: B Test Result: Pass

#### **5.1.1 Used Test Equipment**

Equip. No.	Equipment	Model	Manufacturer
130	ESD Tester	NSG 438A	TESEQ AG
403-550/1712	Impulse Module	INA 4380- 150pF/330Ohm	TESEQ AG



#### 5.1.2 Block Diagram of Test Setup



Note: HCP means <u>Horizontal Coupling Plane</u>, VCP means <u>Vertical Coupling Plane</u> GRP means Ground Reference Plane

#### 5.1.3 Test Setup and Procedure

The EUT was put on a 0.8m high wooden tabel/0.1m high for floor standing equipment standing on the ground reference plane(GRP) 3m by 2m in size, made by iron 1.0 mm thick.

A horizontal coupling plane(HCP) 1.6m by 0.8m in size was placed on the table, and the EUT with its cables were isolated from the HCP by an insulating support thick than 0.5mm. The VCP 0.5m by 0.5m in size & HCP were constructed from the same material type & thinkmess as that of the GRP, and connected to the GRP via a  $470k\Omega$  resistor at each end.

The distance between EUT and any of the other metallic surface excepted the GRP, HCP & VCP was greater than 1m.

The EUT was arranged and connected according to its functional requirements. The EUT was arranged and connected according to its functional requirements

Direct static electricity discharges was applied only to those points and surface which are accessible to personnel during normal usage.

Test voltage was increased from the minimum to the selected test level and with single discharge.



On each preselected points 10 times of each polarity single discharge were applied The time interval between successive single discharges is 1s.

The ESD generator was held perpendicular to the surface to which the discharge is applied. The discharge return cable of the generator was kept at a distance of 0.2m whilst the discharge is being applied. During the contact discharges, the tip of the discharge electrode was touch the EUT before the discharge switch is operated. During the air discharges, the round discharge tip of the discharge electrode was approached as fast as possible to touch the EUT.

Indirect discharge was conducted to objects placed near the EUT, simulated by applying the dischares of the ESD generator to a coupling plane, in the contact discharge mode.

After each discharge, the ESD generator was removed from the EUT, the generator is then retriggered for a new single discharge. For ungrounded product, a grounded carbon fibre brush with bleeder resistors  $(2 \times 470 \text{ k}\Omega)$  in the grounding cable was used after each discharge to remove remnant electrostatic voltage.

10 times of each polarity single discharge were applied to HCP and VCP. The detail selected points are listed in the following table.



#### 5.1.4 Test Result

Direct Application	on of ESD		
Direct Contact Di	scharge		
Applied Voltage (kV)	No. of Discharge for each point	Discharged Points	Result
4	20	Accessible metal parts of the EUT Conductive substrate with coating which is not declared to be insulating	Pass

#### Direct Air Discharge

Applied Voltage (kV)	No. of Discharge for each point	Discharged Points	Result
8	20	All accessible points where contact discharge cannot be applied such as Displays, Indicators light, Keyboard, Button, Switch, Knob, Air gap, Slots, Hole and so on	Pass

#### Indirect Application of ESD

Horizontal Coupling Plane under the EUT

Applied Voltage (kV)	No. of Discharge for each point	Discharged Point	Result
4	20	At the front edge of each HCP opposite the centre point of each unit of the EUT	Pass

#### Vertical Coupling Plane beside the EUT

Applied Voltage (kV)	No. of Discharge for each point	Discharged Point	Result
4	20	The centre of the vertical edge of the coupling plane	Pass

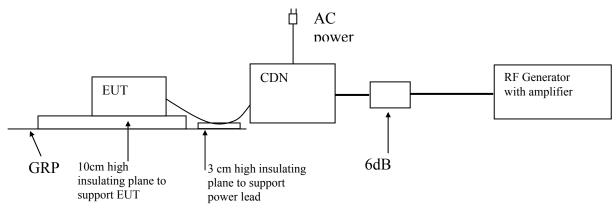


# 5.2 Injected Current (0.15 MHz to 80 MHz) Tested Port: ⊠ AC power ⊠ DC power □Signal/Control Performance criterion: A Test Result: Pass

#### 5.2.1 Used Test Equipment

Equip. No.	Equipment	Model	Manufacturer
0900-12	Simulator	CWS500C	EMTEST
33799	CDN	CDN M532S	TESEQ AG
368	Injection Clamp	F-2031-23MM	EMTEST
0010222A	Attenuator	ATT6	EMTEST
Ec3043-4	CDN	CDN T4	EM TEST

#### 5.2.2 Block Diagram of Test Setup



#### 5.2.3 Test Setup and Procedure

The EUT was placed on an insulating support of 0.1m height above a ground reference Plane, arranged and connected to satisfy its functional requirement.

All relevant cables were provided with the appropriate coupling and decoupling devices at a distance between 0.1m and 0.3m from the projected geometry of the EUT on an insulating support of 0.03m height above the ground reference plane.

Test voltage was verified before each testing though power meter combined in the RF generator with AMP.

Dwell time was set to 3s and step was set as 1% to keep sufficient response time for EUT. The frequency from 0.15MHz to 80MHz was checked.



#### 5.2.4 Test Result

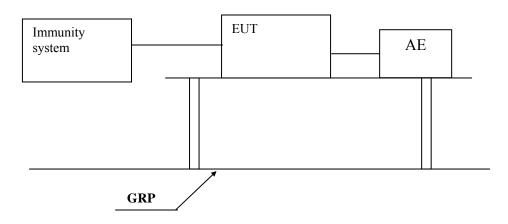
Port	Frequency (MHz)	Level	Result
A.C. Power Lines	0.15 to 80	3V (r.m.s.)	Pass
D.C. Power Lines	0.15 to 80	3V (r.m.s.)	Pass
Signal/Control Lines	0.15 to 80	3V (r.m.s.)	N/A

#### 5.3 Electrical Fast Transient/Burst Tested Port: ⊠ AC power ⊠ DC power □Signal/Control Performance criterion: B Test Result: Pass

#### 5.3.1 Used Test Equipment

Equip. No.	Equipment	Model	Manufacturer
080981-16	Burst Tester	PEFT4010	HAEFELY
147147	Coupling Clamp	IP-4A	HAEFELY

#### 5.3.2 Block Diagram of Test Setup



#### 5.3.3 Test Setup and Procedure

The EUT was placed on a 0.1m high wooden table, standing on the ground reference plane 3m by 2m in size, made by steel 1mm thick.

The distance between the EUT and any other of the metallic surface except the GRP is greater than 0.5m.



The mains lead excess than 0.5m is folded to avoid a flat coil and situated at a distance of 0.1m above the ground reference plane to insure the distance between the coupling device and the EUT were 0.5m.

The EUT was arranged and connected to satisfy its functional requirement and supplied by the coupling-decoupling network.

#### 5.3.4 Test Result

Port	Level	Result
A.C. Power Lines	1kV(Repetition frequency=5KHz, Tr/Th=5ns/50ns)	Pass
D.C. Power Lines	0.5kV(Repetition frequency=5KHz, Tr/Th=5ns/50ns)	Pass
Signal/Control Lines	0.5kV(Repetition frequency=5KHz, Tr/Th=5ns/50ns)	N/A

#### 5.4 Surge Immunity

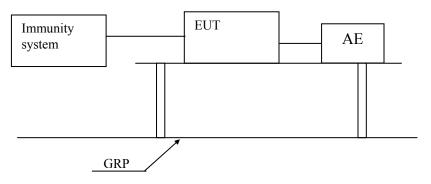
Tested Port: X AC power DC Performance criterion: B Test Result: Pass

**DC** power

#### 5.4.1 Used Test Equipment

Equip. No.	Equipment	Model	Manufacturer
174031	Surge Controller	Psurge 8000	HAEFELY
174124	Impulse Module	PIM 100	HAEFELY
172181	Coupling Decoupling Filter	PCD 130	HAEFELY

#### 5.4.2 Block Diagram of Test Setup



#### 5.4.3 Test Setup and Procedure

The surge is to be applied to the EUT power supply terminals via the capacitive coupling network.



Decoupling networks are required in order to avoid possible adverse effects on equipment not under test that may be powered by the same lines and to provide sufficient decoupling impedance to the surge wave so that the specified wave may be developed on the lines under test.

The EUT was arranged and connected according to its functional requirements The EUT was placed on a 0.1m high wooden support above the GRP, supplied by the couplingdecoupling network, and arranged and connected to satisfy its functional requirement and the power cord between the EUT and the coupling/decoupling network was less than 2 meters.

Surge is applied to the EUT power supply terminals.

Tested Port	Level	Result
AC power	Line to line $\pm 1 \text{ kV}$ (Tr/Th= 8µs/20µs)	Pass
AC power	Line to earth $\pm 2kV$ (Tr/Th= 1.2 $\mu$ s/50 $\mu$ s)	Pass
DC power	Line to line $\pm 0.5$ kV (Tr/Th= 8µs/20µs)	N/A
DC power	Line to earth $\pm 0.5$ kV (Tr/Th= $1.2\mu$ s/50 $\mu$ s)	N/A

#### 5.4.4 Test Result

#### 5.5 Voltage Dips and Interruptions

#### **Tested Port: AC power**

Performance criterion: B (for test level of 0%Ut with 0.5/1 cycles), C (for test level of 70%Ut or 0%Ut with 25 cycles at 50Hz, as well as 30 cycles at 60Hz) Test Result: Not Applicable

**Remark:** The rated current is greater than 16A/phase.

# 5.6 Radiated Electromagnetic Field Immunity

Tested Port: Enclosure Performance criterion: A Test Result: Pass

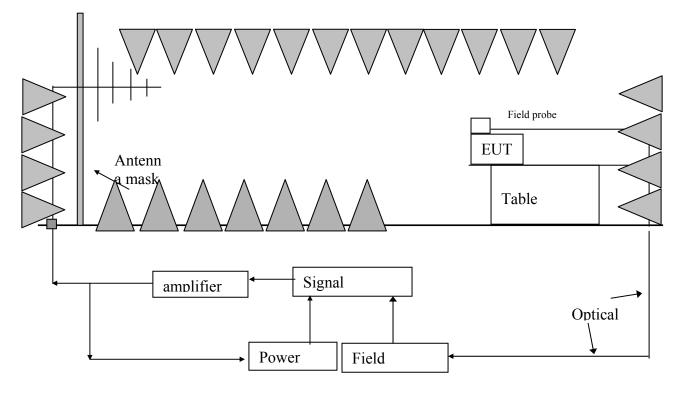
Equipment No.	Equipment	Model	Manufacturer
10539	RF Power Meter. Dual Channel	4232A	BOONTON
34236/34238	50ohm Diode Power Sensor	51011EMC	BOONTON
332	Broad-Band Horn Antenna	BBHA 9120 L3F	SCHWARZBECK

#### 5.6.1 Used Test Equipment



N/A	Power Amplifier	AP32MT215	PRANA
N/A	Power Amplifier	AS0102-55	MILMEGA
N/A	Signal Generator	2023B	AEROFLEX
N/A	LogPer. Antenna	VULP 9118E	SCHWARZBECK

#### 5.6.2 Block Diagram of Test Setup





### 5.6.3 Test Setup and Procedure

The test was conducted in an fully anechoic chamber to maintain a uniform field of sufficient dimensions with respect to the EUT, and also in order to comply with various national and international laws prohibiting interference to radio communications.

The equipment is placed in the test facility on a non-conducting table 0.8m high (for floor standing EUT, is placed on a non-conducting support 0.1m height).

The EUT was placed on the uniform calibrated plane which is 10V/m, 3V/m and 1V/m EM field.

For all ports connected to EUT, manufacturer specified cable type and length was used, for those cables no specification, unshielded cable applied.

Wire is left exposed to the electromagnetic field for a distance of 1m from the EUT.

The EUT was arranged and connected according to its functional requirements

Before testing, the intensity of the established field strength have been checked by placing the field sensor at a calibration grid point, and with the field generating antenna and cables in the



same positions as used for the calibration, the forward power needed to give the calibrated field strength was measured.

Spot checks was made at a number of calibration grid points over the frequency range 80 to 1000MHz and 1.4 to 2.7 GHz, both polarizations was checked.

After calibration, the EUT is initially placed with one face coincident with the calibration plane. The frequency range is swept from 80 to 1000MHz and 1.4 to 2.7 GH, with the signal 80% amplitude modulated with a 1 kHz sinewave, pausing to adjust the r.f. signal level. The dwell time at each frequency was 3s so as that the EUT to be exercised and be able to respond.

The step size was 1% of the fundamental with linear interpolation between calibrated points. Test was performed with the generating antenna facing each of the four sides of the EUT.

Frequency (MHz)	Exposed Side	Field Strength (V/m)	Result
80 to 1000	Front	3V/m (r.m.s.)	Pass
80 to 1000	Left	3V/m (r.m.s.)	Pass
80 to 1000	Rear	3V/m (r.m.s.)	Pass
80 to 1000	Right	3V/m (r.m.s.)	Pass

5.6.4	Test	Result

Frequency (GHz)	Exposed Side	Field Strength (V/m)	Result
1.4 to 2.0	Front	3V/m (r.m.s.)	Pass
1.4 to 2.0	Left	3V/m (r.m.s.)	Pass
1.4 to 2.0	Rear	3V/m (r.m.s.)	Pass
1.4 to 2.0	Right	3V/m (r.m.s.)	Pass

Frequency (GHz)	Exposed Side	Field Strength (V/m)	Result
2.0 to 2.7	Front	1V/m (r.m.s.)	Pass
2.0 to 2.7	Left	1V/m (r.m.s.)	Pass
2.0 to 2.7	Rear	1V/m (r.m.s.)	Pass
2.0 to 2.7	Right	1V/m (r.m.s.)	Pass

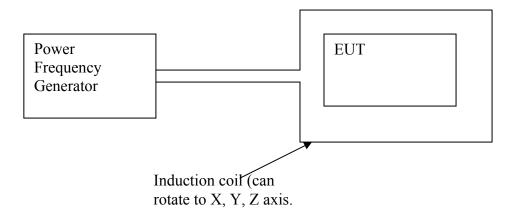


5.7 Power Frequency Magnetic Field Immunity Tested Port: Enclosure Performance criterion: A Test Result: Pass

### 5.7.1 Used Test Equipment

Equipment No.	Equipment	Model	Manufacturer
250040.1	Magnetic Field Tester	MAG100	HAEFELY

### 5.7.2 Block Diagram of Test Setup



#### 5.7.3 Test Setup and Procedure

Put EUT into center of induction coil(with suitable dimensions) in the testing.

For tabletop equipment:

The EUT was placed on a big enough wooden desk with height of 0.8m and operating as intended.

The equipment shall be subjected to the test magnetic field by using the induction coil of standards(1m\*1m).

The induction coil shall be rotated by  $90^{\circ}$  in order to expose the EUT to the test field with different orientations.

For Floor-standing equipment:

The EUT was placed on big enough wooden desk with height of 0.1m and operating as intended. The equipment shall be subjected to the test magnetic field by using induction coils of suitable dimensions ; the test shall be repeated by moving and shifting the induction coils, in order to test the whole volume of the EUT for each orthogonal direction. The test shall be repeated with the coil shifted to different position along the side of the EUT, in steps corresponding to 50% of the shortest side of the coil.

The induction coil shall then be rotated by  $90^0$  in order to expose the EUT to the test field with different orientations and the same procedure followed.



### 5.7.4 Test Result

Mains frequency: 🗵 50Hz	□ 60Hz	
Orientations of induction coil	Magnetic Field Strength (A/m)	Result
Х	3A/m	Pass
Y	3A/m	Pass
Z	3A/m	Pass



# 6 Appendix I - Photos of test setup

Continuous/Discontinuous conducted disturbance voltage



Radiated emission (30 MHz-1000 MHz)







Harmonic of current & Flicker







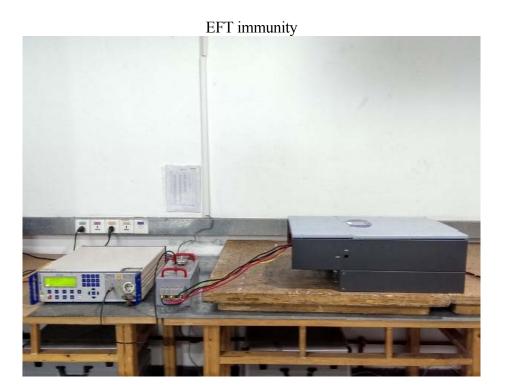


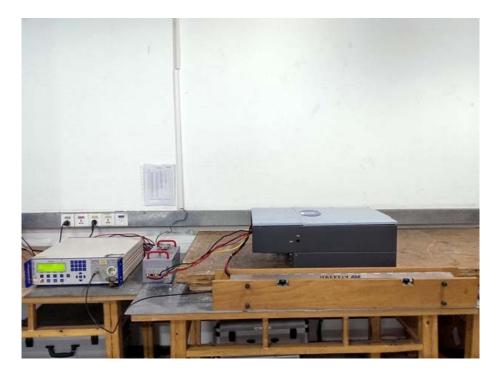
Radiated EM field immunity (80-1000MHz)

Radiated EM field immunity (1400-2700MHz)









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Inject current immunity







SURGE immunity

Power frequency magnetic field immunity

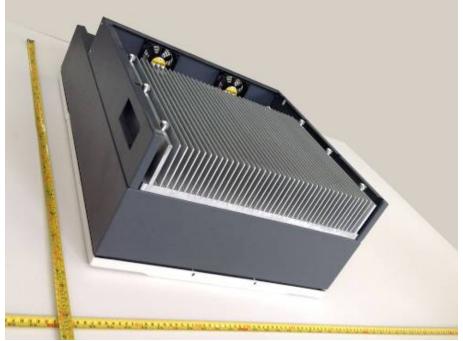




# 7 Appendix II- Photos of EUT

<image>

## Bottom view of the unit



Overall view of the unit



Terminals view of the unit (for models "-S2" to "-S6") PV connector (Sofar 20000TL-Sx and Sofar 17000TL-Sx has 3×2 pairs) (Sofar 15000TL-Sx and Sofar 10000TL-Sx has 2×2 pairs)



Terminals view of the unit (for models "-S0" to "-S1") DC Çable Gland



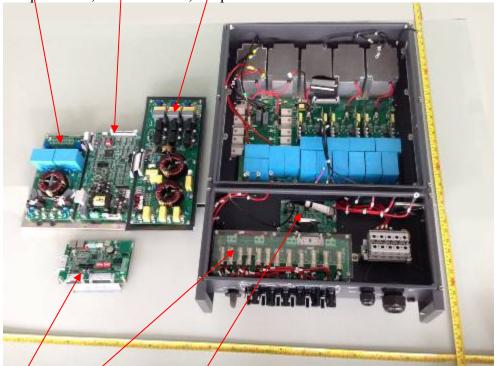




Internal view of the unit

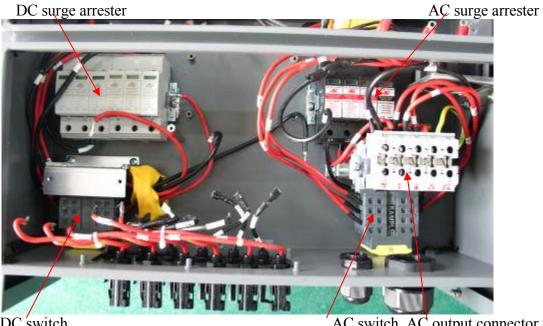






Internal view of the unit Input board, Control board, Output board

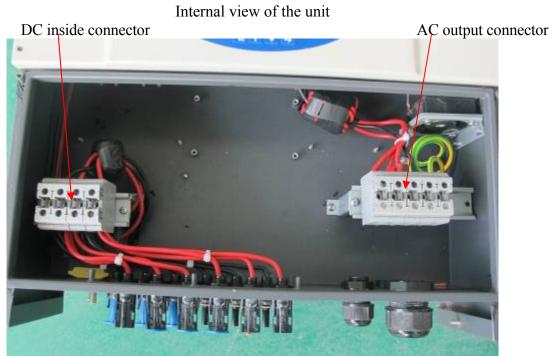
COM board, Fuse board, String detection board



DC switch

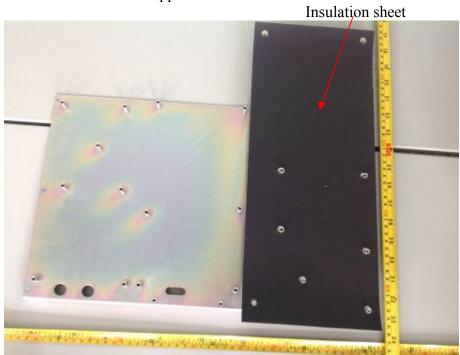
AC switch, AC output connector









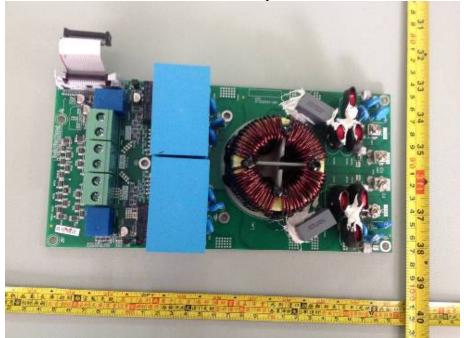


Support board for the PCBs

# Cavity view of the enclosure

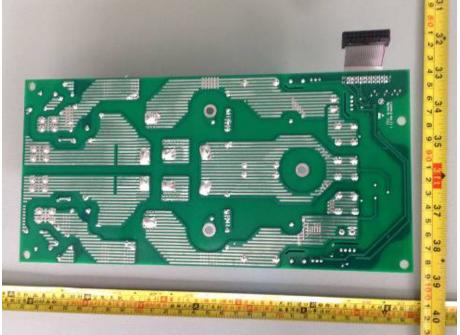






# Front view of the input board

Bottom view of the input board







Front view of the control board

Bottom view of the control board

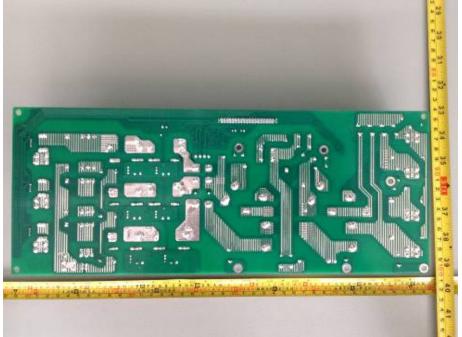




# Front view of the output board



Bottom view of the output board

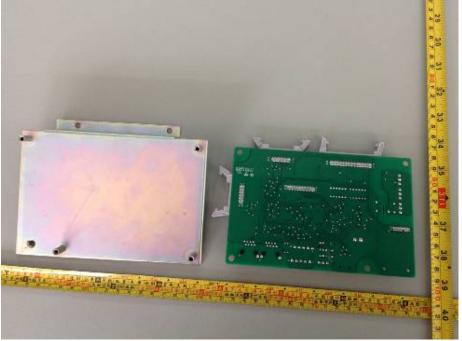






## Front view of the COM board

Bottom view of the COM board







### Front view of the fuse board

Bottom view of the fuse board







Front view of the string detection board

Bottom view of the string detection board

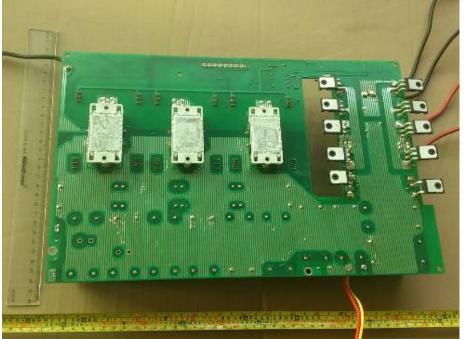




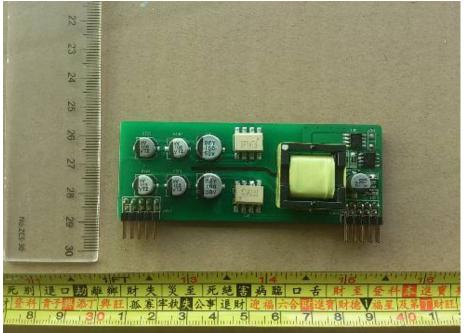


Front view of the power board

Bottom view of the power board

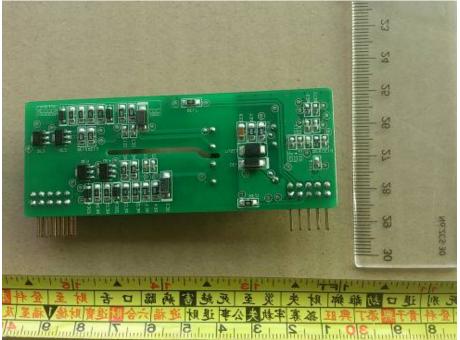






### Front view of the driver board

Bottom view of the driver board







Front view of the display board

Bottom view of the display board

